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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	6000
Number of Logic Elements/Cells	76800
Total RAM Bits	4331520
Number of I/O	338
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	484-BGA
Supplier Device Package	484-FPBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc7s75-2fgga484c

Table 1: Absolute Maximum Ratings⁽¹⁾ (Cont'd)

Symbol	Description	Min	Max	Units
$V_{IN}^{(2)(3)(4)}$	I/O input voltage.	−0.4	$V_{CCO} + 0.55$	V
	I/O input voltage (when $V_{CCO} = 3.3V$) for V_{REF} and differential I/O standards except TMDS_33. ⁽⁵⁾	−0.4	2.625	V
V_{CCBATT}	Key memory battery backup supply.	−0.5	2.0	V
XADC				
V_{CCADC}	XADC supply relative to GNDADC.	−0.5	2.0	V
V_{REFP}	XADC reference input relative to GNDADC.	−0.5	2.0	V
Temperature				
T_{STG}	Storage temperature (ambient).	−65	150	°C
T_{SOL}	Maximum soldering temperature for Pb/Sn component bodies. ⁽⁶⁾	—	+220	°C
	Maximum soldering temperature for Pb-free component bodies. ⁽⁶⁾	—	+260	°C
T_j	Maximum junction temperature. ⁽⁶⁾	—	+125	°C

Notes:

- Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.
- The lower absolute voltage specification always applies.
- For I/O operation, refer to the *7 Series FPGAs SelectIO Resources User Guide* (UG471) [Ref 3].
- The maximum limit applies to DC signals. For maximum undershoot and overshoot AC specifications, see Table 4.
- See Table 9 for TMDS_33 specifications.
- For soldering guidelines and thermal considerations, see the *7 Series FPGA Packaging and Pinout Specification* (UG475) [Ref 4].

Table 2: Recommended Operating Conditions⁽¹⁾⁽²⁾

Symbol	Description	Min	Typ	Max	Units
FPGA Logic					
$V_{CCINT}^{(3)}$	For -2 and -1 (1.0V) devices: internal supply voltage.	0.95	1.00	1.05	V
	For -1L (0.95V) devices: internal supply voltage.	0.92	0.95	0.98	V
V_{CCAUX}	Auxiliary supply voltage.	1.71	1.80	1.89	V
$V_{CCBRAM}^{(3)}$	For -2 and -1 (1.0V) devices: block RAM supply voltage.	0.95	1.00	1.05	V
	For -1L (0.95V) devices: block RAM supply voltage.	0.92	0.95	0.98	V
$V_{CCO}^{(4)(5)}$	Supply voltage for HR I/O banks.	1.14	–	3.465	V
$V_{IN}^{(6)}$	I/O input voltage.	–0.20	–	$V_{CCO} + 0.20$	V
	I/O input voltage (when $V_{CCO} = 3.3V$) for V_{REF} and differential I/O standards except TMD5_33. ⁽⁷⁾	–0.20	–	2.625	V
$I_{IN}^{(8)}$	Maximum current through any pin in a powered or unpowered bank when forward biasing the clamp diode.	–	–	10	mA
$V_{CCBATT}^{(9)}$	Battery voltage.	1.0	–	1.89	V
XADC					
V_{CCADC}	XADC supply relative to GNDADC.	1.71	1.80	1.89	V
V_{REFP}	Externally supplied reference voltage.	1.20	1.25	1.30	V
Temperature					
T_j	Junction temperature operating range for commercial (C) temperature devices.	0	–	85	°C
	Junction temperature operating range for industrial (I) temperature devices.	–40	–	100	°C
	Junction temperature operating range for expanded (Q) temperature devices.	–40	–	125	°C

Notes:

- All voltages are relative to ground.
- For the design of the power distribution system consult the *7 Series FPGAs PCB Design Guide* (UG483) [Ref 5].
- If V_{CCINT} and V_{CCBRAM} are operating at the same voltage, V_{CCINT} and V_{CCBRAM} should be connected to the same supply.
- Configuration data is retained even if V_{CCO} drops to 0V.
- Includes V_{CCO} of 1.2V, 1.35V, 1.5V, 1.8V, 2.5V, and 3.3V at $\pm 5\%$.
- The lower absolute voltage specification always applies.
- See Table 9 for TMD5_33 specifications.
- A total of 200 mA per bank should not be exceeded.
- V_{CCBATT} is required only when using bitstream encryption. If battery is not used, connect V_{CCBATT} to either ground or V_{CCAUX} .

Table 4: V_{IN} Maximum Allowed AC Voltage Overshoot and Undershoot for HR I/O Banks⁽¹⁾⁽²⁾

AC Voltage Overshoot	% of UI at –40°C to 125°C	AC Voltage Undershoot	% of UI at –40°C to 125°C
$V_{CCO} + 0.55$	100	–0.40	100
		–0.45	61.7
		–0.50	25.8
		–0.55	11.0
$V_{CCO} + 0.60$	46.6	–0.60	4.77
$V_{CCO} + 0.65$	21.2	–0.65	2.10
$V_{CCO} + 0.70$	9.75	–0.70	0.94
$V_{CCO} + 0.75$	4.55	–0.75	0.43
$V_{CCO} + 0.80$	2.15	–0.80	0.20
$V_{CCO} + 0.85$	1.02	–0.85	0.09
$V_{CCO} + 0.90$	0.49	–0.90	0.04
$V_{CCO} + 0.95$	0.24	–0.95	0.02

Notes:

1. A total of 200 mA per bank should not be exceeded.
2. The peak voltage of the overshoot or undershoot, and the duration above $V_{CCO} + 0.20V$ or below $GND - 0.20V$, must not exceed the values in this table.

Table 5: Typical Quiescent Supply Current⁽¹⁾⁽²⁾⁽³⁾

Symbol	Description	Device	Speed Grade						Units
			1.0V					0.95V	
			-2C	-2I	-1C	-1I	-1Q	-1LI	
I_{CCINTQ}	Quiescent V_{CCINT} supply current.	XC7S6	36	36	36	36	36	32	mA
		XC7S15	36	36	36	36	36	32	mA
		XC7S25	48	48	48	48	48	43	mA
		XC7S50	95	95	95	95	95	59	mA
		XC7S75	148	148	148	148	148	134	mA
		XC7S100	148	148	148	148	148	134	mA
		XA7S6	N/A	36	N/A	36	36	N/A	mA
		XA7S15	N/A	36	N/A	36	36	N/A	mA
		XA7S25	N/A	48	N/A	48	48	N/A	mA
		XA7S50	N/A	95	N/A	95	95	N/A	mA
		XA7S75	N/A	148	N/A	148	148	N/A	mA
		XA7S100	N/A	148	N/A	148	148	N/A	mA

Table 5: Typical Quiescent Supply Current⁽¹⁾⁽²⁾⁽³⁾ (Cont'd)

Symbol	Description	Device	Speed Grade						Units
			1.0V					0.95V	
			-2C	-2I	-1C	-1I	-1Q	-1LI	
$I_{CCBRAMQ}$	Quiescent V_{CCBRAM} supply current.	XC7S6	1	1	1	1	1	1	mA
		XC7S15	1	1	1	1	1	1	mA
		XC7S25	1	1	1	1	1	1	mA
		XC7S50	2	2	2	2	2	1	mA
		XC7S75	9	9	9	9	9	8	mA
		XC7S100	9	9	9	9	9	8	mA
		XA7S6	N/A	1	N/A	1	1	N/A	mA
		XA7S15	N/A	1	N/A	1	1	N/A	mA
		XA7S25	N/A	1	N/A	1	1	N/A	mA
		XA7S50	N/A	2	N/A	2	2	N/A	mA
		XA7S75	N/A	9	N/A	9	9	N/A	mA
		XA7S100	N/A	9	N/A	9	9	N/A	mA

Notes:

- Typical values are specified at nominal voltage, 85°C junction temperature (T_j) with single-ended SelectIO™ resources.
- Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
- Use the *Xilinx Power Estimator* spreadsheet tool [Ref 6] to estimate static power consumption for conditions other than those specified.

Power-On/Off Power Supply Sequencing

The recommended power-on sequence is V_{CCINT} , V_{CCBRAM} , V_{CCAUX} , and V_{CCO} to achieve minimum current draw and ensure that the I/Os are 3-stated at power-on. The recommended power-off sequence is the reverse of the power-on sequence. If V_{CCINT} and V_{CCBRAM} have the same recommended voltage levels then both can be powered by the same supply and ramped simultaneously. If V_{CCAUX} and V_{CCO} have the same recommended voltage levels then both can be powered by the same supply and ramped simultaneously.

For V_{CCO} voltages of 3.3V in HR I/O banks and configuration bank 0 the following conditions apply.

- The voltage difference between V_{CCO} and V_{CCAUX} must not exceed 2.625V for longer than $T_{VCCO2VCCAUX}$ for each power-on/off cycle to maintain device reliability levels.
- The $T_{VCCO2VCCAUX}$ time can be allocated in any percentage between the power-on and power-off ramps.

There is no recommended sequence for supplies not discussed in this section.

LVDS DC Specifications (LVDS_25)

Table 11: LVDS_25 DC Specifications⁽¹⁾

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply voltage.		2.375	2.500	2.625	V
V_{OH}	Output High voltage for Q and $\overline{Q}$.	$R_T = 100\Omega$ across Q and $\overline{Q}$ signals.	–	–	1.675	V
V_{OL}	Output Low voltage for Q and $\overline{Q}$.	$R_T = 100\Omega$ across Q and $\overline{Q}$ signals.	0.700	–	–	V
V_{ODIFF}	Differential output voltage: (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High	$R_T = 100\Omega$ across Q and $\overline{Q}$ signals.	247	350	600	mV
V_{OCM}	Output common-mode voltage.	$R_T = 100\Omega$ across Q and $\overline{Q}$ signals.	1.000	1.250	1.425	V
V_{IDIFF}	Differential input voltage: (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High		100	350	600	mV
V_{ICM}	Input common-mode voltage.		0.300	1.200	1.500	V

Notes:

1. Differential inputs for LVDS_25 can be placed in banks with V_{CCO} levels that are different from the required level for outputs. Consult the *7 Series FPGAs SelectIO Resources User Guide* (UG471) [Ref 3] for more information.

Table 14: Spartan-7 Device Production Software and Speed Specification Release

Device	V_{CCINT} Operating Voltage, Speed Grade, and Temperature Range					
	1.0V					0.95V
	-2C	-2I	-1C	-1I	-1Q	-1LI
XC7S6	Vivado tools 2018.2 v1.22				Vivado tools 2018.2.1 v1.23	Vivado tools 2018.2 v1.22
XC7S15	Vivado tools 2018.2 v1.22				Vivado tools 2018.2.1 v1.23	Vivado tools 2018.2 v1.22
XC7S25	Vivado tools 2017.4 v1.20				Vivado tools 2018.1 v1.21	Vivado tools 2017.4 v1.20
XC7S50	Vivado tools 2017.2 v1.17				Vivado tools 2017.3 v1.19	Vivado tools 2017.2 v1.17
XC7S75	Vivado tools 2018.1 v1.21				Vivado tools 2018.2.1 v1.23	Vivado tools 2018.1 v1.21
XC7S100	Vivado tools 2018.1 v1.21				Vivado tools 2018.2.1 v1.23	Vivado tools 2018.1 v1.21
XA7S6	N/A	Vivado tools 2018.2.1 v1.16	N/A	Vivado tools 2018.2.1 v1.16		N/A
XA7S15	N/A	Vivado tools 2018.2.1 v1.16	N/A	Vivado tools 2018.2.1 v1.16		N/A
XA7S25	N/A	Vivado tools 2018.1 v1.15	N/A	Vivado tools 2018.1 v1.15		N/A
XA7S50	N/A	Vivado tools 2017.3 v1.12	N/A	Vivado tools 2017.3 v1.12		N/A
XA7S75	N/A	Vivado tools 2018.2.1 v1.16	N/A	Vivado tools 2018.2.1 v1.16		N/A
XA7S100	N/A	Vivado tools 2018.2.1 v1.16	N/A	Vivado tools 2018.2.1 v1.16		N/A

Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Spartan-7 FPGAs. These values are subject to the same guidelines as the [AC Switching Characteristics, page 12](#).

Table 15: Networking Applications Interface Performances

Description	V_{CCINT} Operating Voltage, Speed Grade, and Temperature Range			Units
	1.0V		0.95V	
	-2C/-2I	-1C/-1I/-1Q	-1LI	
SDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 8)	680	600	600	Mb/s
DDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 14)	1250	950	950	Mb/s
SDR LVDS receiver ⁽¹⁾	680	600	600	Mb/s

Table 20: Output Delay Measurement Methodology

Description	I/O Standard Attribute	R _{REF} (Ω)	C _{REF} ⁽¹⁾ (pF)	V _{MEAS} (V)	V _{REF} (V)
LVC MOS, 1.2V	LVC MOS12	1M	0	0.6	0
LVC MOS, 1.5V	LVC MOS15	1M	0	0.75	0
LVC MOS, 1.8V	LVC MOS18	1M	0	0.9	0
LVC MOS, 2.5V	LVC MOS25	1M	0	1.25	0
LVC MOS, 3.3V	LVC MOS33	1M	0	1.65	0
LVTTL, 3.3V	LVTTL	1M	0	1.65	0
PCI33, 3.3V	PCI33_3	25	10	1.65	0
HSTL (high-speed transceiver logic), Class I, 1.2V	HSTL_I_12	50	0	V _{REF}	0.6
HSTL, Class I, 1.5V	HSTL_I	50	0	V _{REF}	0.75
HSTL, Class II, 1.5V	HSTL_II	25	0	V _{REF}	0.75
HSTL, Class I, 1.8V	HSTL_I_18	50	0	V _{REF}	0.9
HSTL, Class II, 1.8V	HSTL_II_18	25	0	V _{REF}	0.9
HSUL (high-speed unterminated logic), 1.2V	HSUL_12	50	0	V _{REF}	0.6
SSTL12, 1.2V	SSTL12	50	0	V _{REF}	0.6
SSTL135/SSTL135_R, 1.35V	SSTL135, SSTL135_R	50	0	V _{REF}	0.675
SSTL15/SSTL15_R, 1.5V	SSTL15, SSTL15_R	50	0	V _{REF}	0.75
SSTL (stub-series terminated logic), Class I & Class II, 1.8V	SSTL18_I, SSTL18_II	50	0	V _{REF}	0.9
DIFF_MOBILE_DDR, 1.8V	DIFF_MOBILE_DDR	50	0	V _{REF}	0.9
DIFF_HSTL, Class I, 1.2V	DIFF_HSTL_I_12	50	0	V _{REF}	0.6
DIFF_HSTL, Class I & II, 1.5V	DIFF_HSTL_I, DIFF_HSTL_II	50	0	V _{REF}	0.75
DIFF_HSTL, Class I & II, 1.8V	DIFF_HSTL_I_18, DIFF_HSTL_II_18	50	0	V _{REF}	0.9
DIFF_HSUL_12, 1.2V	DIFF_HSUL_12	50	0	V _{REF}	0.6
DIFF_SSTL135/DIFF_SSTL135_R, 1.35V	DIFF_SSTL135, DIFF_SSTL135_R	50	0	V _{REF}	0.675
DIFF_SSTL15/DIFF_SSTL15_R, 1.5V	DIFF_SSTL15, DIFF_SSTL15_R	50	0	V _{REF}	0.75
DIFF_SSTL18, Class I & II, 1.8V	DIFF_SSTL18_I, DIFF_SSTL18_II	50	0	V _{REF}	0.9
LVDS, 2.5V	LVDS_25	100	0	0 ⁽²⁾	0
BLVDS (Bus LVDS), 2.5V	BLVDS_25	100	0	0 ⁽²⁾	0
Mini LVDS, 2.5V	MINI_LVDS_25	100	0	0 ⁽²⁾	0
PPDS_25	PPDS_25	100	0	0 ⁽²⁾	0
RS DS_25	RS DS_25	100	0	0 ⁽²⁾	0
TMDS_33	TMDS_33	50	0	0 ⁽²⁾	3.3

Notes:

1. C_{REF} is the capacitance of the probe, nominally 0 pF.
2. The value given is the differential output voltage.

Input/Output Logic Switching Characteristics

Table 21: ILOGIC Switching Characteristics

Symbol	Description	V _{CCINT} Operating Voltage and Speed Grade			Units
		1.0V		0.95V	
		-2	-1	-1L	
Setup/Hold					
T _{ICE1CK} /T _{ICKCE1}	CE1 pin setup/hold with respect to CLK.	0.54/0.02	0.76/0.02	0.76/0.02	ns
T _{ISRCK} /T _{ICKSR}	SR pin setup/hold with respect to CLK.	0.70/0.01	1.13/0.01	1.13/0.01	ns
T _{IDOCK} /T _{IOCKD}	D pin setup/hold with respect to CLK without delay.	0.01/0.29	0.01/0.33	0.01/0.33	ns
T _{IDOCKD} /T _{IOCKDD}	DDL pin setup/hold with respect to CLK (using IDELAY).	0.02/0.29	0.02/0.33	0.02/0.33	ns
Combinatorial					
T _{IDI}	D pin to O pin propagation delay, no delay.	0.11	0.13	0.13	ns
T _{IDID}	DDL pin to O pin propagation delay (using IDELAY).	0.12	0.14	0.14	ns
Sequential Delays					
T _{IDLO}	D pin to Q1 pin using flip-flop as a latch without delay.	0.44	0.51	0.51	ns
T _{IDLOD}	DDL pin to Q1 pin using flip-flop as a latch (using IDELAY).	0.44	0.51	0.51	ns
T _{ICKQ}	CLK to Q outputs.	0.57	0.66	0.66	ns
T _{RQ_ILOGIC}	SR pin to OQ/TQ out.	1.08	1.32	1.32	ns
T _{GSRQ_ILOGIC}	Global set/reset to Q outputs.	7.60	10.51	10.51	ns
Set/Reset					
T _{RPW_ILOGIC}	Minimum pulse width, SR inputs.	0.72	0.72	0.72	ns, Min

Input Serializer/Deserializer Switching Characteristics

Table 23: ISERDES Switching Characteristics

Symbol	Description	V _{CCINT} Operating Voltage and Speed Grade			Units
		1.0V		0.95V	
		-2	-1	-1L	
Setup/Hold for Control Lines					
T _{ISCKC_BITSLIP} / T _{ISCKC_BITSLIP}	BITSLIP pin setup/hold with respect to CLKDIV.	0.02/0.15	0.02/0.17	0.02/0.17	ns
T _{ISCKC_CE} / T _{ISCKC_CE}	CE pin setup/hold with respect to CLK (for CE1).	0.50/−0.01	0.72/−0.01	0.72/−0.01	ns
T _{ISCKC_CE2} / T _{ISCKC_CE2}	CE pin setup/hold with respect to CLKDIV (for CE2).	−0.10/0.36	−0.10/0.40	−0.10/0.40	ns
Setup/Hold for Data Lines					
T _{ISDCK_D} / T _{ISCKD_D}	D pin setup/hold with respect to CLK.	−0.02/0.14	−0.02/0.17	−0.02/0.17	ns
T _{ISDCK_DDLY} / T _{ISCKD_DDLY}	DDLY pin setup/hold with respect to CLK (using IDELAY). ⁽¹⁾	−0.02/0.14	−0.02/0.17	−0.02/0.17	ns
T _{ISDCK_D_DDR} / T _{ISCKD_D_DDR}	D pin setup/hold with respect to CLK at DDR mode.	−0.02/0.14	−0.02/0.17	−0.02/0.17	ns
T _{ISDCK_DDLY_DDR} / T _{ISCKD_DDLY_DDR}	D pin setup/hold with respect to CLK at DDR mode (using IDELAY). ⁽¹⁾	0.14/0.14	0.17/0.17	0.17/0.17	ns
Sequential Delays					
T _{ISCKO_Q}	CLKDIV to out at Q pin.	0.54	0.66	0.66	ns
Propagation Delays					
T _{ISDO_DO}	D input to DO output pin.	0.11	0.13	0.13	ns

Notes:

- Recorded at 0 tap value.

CLB Switching Characteristics

Table 27: CLB Switching Characteristics

Symbol	Description	V _{CCINT} Operating Voltage and Speed Grade			Units
		1.0V		0.95V	
		-2	-1	-1L	
Combinatorial Delays					
T _{ILO}	An – Dn LUT address to A.	0.11	0.13	0.13	ns, Max
T _{ILO_2}	An – Dn LUT address to AMUX/CMUX.	0.30	0.36	0.36	ns, Max
T _{ILO_3}	An – Dn LUT address to BMUX_A.	0.46	0.55	0.55	ns, Max
T _{ITO}	An – Dn inputs to A – D Q outputs.	1.05	1.27	1.27	ns, Max
T _{AXA}	AX inputs to AMUX output.	0.69	0.84	0.84	ns, Max
T _{AXB}	AX inputs to BMUX output.	0.66	0.83	0.83	ns, Max
T _{AXC}	AX inputs to CMUX output.	0.68	0.82	0.82	ns, Max
T _{AXD}	AX inputs to DMUX output.	0.75	0.90	0.90	ns, Max
T _{BXB}	BX inputs to BMUX output.	0.57	0.69	0.69	ns, Max
T _{BXD}	BX inputs to DMUX output.	0.69	0.82	0.82	ns, Max
T _{CXC}	CX inputs to CMUX output.	0.48	0.58	0.58	ns, Max
T _{CXD}	CX inputs to DMUX output.	0.59	0.71	0.71	ns, Max
T _{DXD}	DX inputs to DMUX output.	0.58	0.70	0.70	ns, Max
Sequential Delays					
T _{CKO}	Clock to AQ – DQ outputs.	0.44	0.53	0.53	ns, Max
T _{SHCKO}	Clock to AMUX – DMUX outputs.	0.53	0.66	0.66	ns, Max
Setup and Hold Times of CLB Flip-Flops Before/After Clock CLK					
T _{AS} /T _{AH}	AN – DN input to CLK on A – D flip-flops.	0.09/0.14	0.11/0.18	0.11/0.18	ns, Min
T _{DICK} /T _{CKDI}	AX – DX input to CLK on A – D flip-flops.	0.07/0.21	0.09/0.26	0.09/0.26	ns, Min
	AX – DX input through MUXs and/or carry logic to CLK on A – D flip-flops.	0.66/0.09	0.81/0.11	0.81/0.11	ns, Min
T _{CECK_CLB} / T _{CKCE_CLB}	CE input to CLK on A – D flip-flops.	0.17/0.00	0.21/0.01	0.21/0.01	ns, Min
T _{SRCK} /T _{CKSR}	SR input to CLK on A – D flip-flops.	0.43/0.04	0.53/0.05	0.53/0.05	ns, Min
Set/Reset					
T _{SRMIN}	SR input minimum pulse width.	0.78	1.04	1.04	ns, Min
T _{RQ}	Delay from SR input to AQ – DQ flip-flops.	0.59	0.71	0.71	ns, Max
T _{CEO}	Delay from CE input to AQ – DQ flip-flops.	0.58	0.70	0.70	ns, Max
F _{TOG}	Toggle frequency (for export control).	1286	1098	1098	MHz

Block RAM and FIFO Switching Characteristics

Table 30: Block RAM and FIFO Switching Characteristics

Symbol	Description	V _{CCINT} Operating Voltage and Speed Grade			Units
		1.0V		0.95V	
		-2	-1	-1L	
Block RAM and FIFO Clock-to-Out Delays					
T _{RCKO_DO} and T _{RCKO_DO_REG}	Clock CLK to DOUT output (without output register). ⁽¹⁾⁽²⁾	2.13	2.46	2.46	ns, Max
	Clock CLK to DOUT output (with output register). ⁽³⁾⁽⁴⁾	0.74	0.89	0.89	ns, Max
T _{RCKO_DO_ECC} and T _{RCKO_DO_ECC_REG}	Clock CLK to DOUT output with ECC (without output register). ⁽¹⁾⁽²⁾	3.04	3.84	3.84	ns, Max
	Clock CLK to DOUT output with ECC (with output register). ⁽³⁾⁽⁴⁾	0.81	0.94	0.94	ns, Max
T _{RCKO_DO_CASCOUT} and T _{RCKO_DO_CASCOUT_REG}	Clock CLK to DOUT output with cascade (without output register). ⁽¹⁾	2.88	3.30	3.30	ns, Max
	Clock CLK to DOUT output with cascade (with output register). ⁽³⁾	1.28	1.46	1.46	ns, Max
T _{RCKO_FLAGS}	Clock CLK to FIFO flags outputs. ⁽⁵⁾	0.87	1.05	1.05	ns, Max
T _{RCKO_POINTERS}	Clock CLK to FIFO pointers outputs. ⁽⁶⁾	1.02	1.15	1.15	ns, Max
T _{RCKO_PARITY_ECC}	Clock CLK to ECCPARITY in ECC encode only mode.	0.85	0.94	0.94	ns, Max
T _{RCKO_SDBIT_ECC} and T _{RCKO_SDBIT_ECC_REG}	Clock CLK to BITERR (without output register).	2.81	3.55	3.55	ns, Max
	Clock CLK to BITERR (with output register).	0.76	0.89	0.89	ns, Max
T _{RCKO_RDADDR_ECC} and T _{RCKO_RDADDR_ECC_REG}	Clock CLK to RDADDR output with ECC (without output register).	0.88	1.07	1.07	ns, Max
	Clock CLK to RDADDR output with ECC (with output register).	0.93	1.08	1.08	ns, Max
Setup and Hold Times Before/After Clock CLK					
T _{TRCK_ADDRA} / T _{TRCKC_ADDRA}	ADDR inputs. ⁽⁷⁾	0.49/0.33	0.57/0.36	0.57/0.36	ns, Min
T _{TRDCK_DI_WF_NC} / T _{TRCKD_DI_WF_NC}	Data input setup/hold time when block RAM is configured in WRITE_FIRST or NO_CHANGE mode. ⁽⁸⁾	0.65/0.63	0.74/0.67	0.74/0.67	ns, Min
T _{TRDCK_DI_RF} / T _{TRCKD_DI_RF}	Data input setup/hold time when block RAM is configured in READ_FIRST mode. ⁽⁸⁾	0.22/0.34	0.25/0.41	0.25/0.41	ns, Min
T _{TRDCK_DI_ECC} / T _{TRCKD_DI_ECC}	DIN inputs with block RAM ECC in standard mode. ⁽⁸⁾	0.55/0.46	0.63/0.50	0.63/0.50	ns, Min
T _{TRDCK_DI_ECCW} / T _{TRCKD_DI_ECCW}	DIN inputs with block RAM ECC encode only. ⁽⁸⁾	1.02/0.46	1.17/0.50	1.17/0.50	ns, Min

Table 30: Block RAM and FIFO Switching Characteristics (Cont'd)

Symbol	Description	V _{CCINT} Operating Voltage and Speed Grade			Units
		1.0V		0.95V	
		-2	-1	-1L	
T _{RDCK_DI_ECC_FIFO} / T _{RCKD_DI_ECC_FIFO}	DIN inputs with FIFO ECC in standard mode. ⁽⁸⁾	1.15/0.59	1.32/0.64	1.32/0.64	ns, Min
T _{RCKC_INJECTBITERR} / T _{RCKC_INJECTBITERR}	Inject single/double bit error in ECC mode.	0.64/0.37	0.74/0.40	0.74/0.40	ns, Min
T _{RCKC_EN} /T _{RCKC_EN}	Block RAM enable (EN) input.	0.39/0.21	0.45/0.23	0.45/0.23	ns, Min
T _{RCKC_REGCE} / T _{RCKC_REGCE}	CE input of output register.	0.29/0.15	0.36/0.16	0.36/0.16	ns, Min
T _{RCKC_RSTREG} / T _{RCKC_RSTREG}	Synchronous RSTREG input.	0.32/0.07	0.35/0.07	0.35/0.07	ns, Min
T _{RCKC_RSTRAM} / T _{RCKC_RSTRAM}	Synchronous RSTRAM input.	0.34/0.43	0.36/0.46	0.36/0.46	ns, Min
T _{RCKC_WEA} /T _{RCKC_WEA}	Write enable (WE) input (block RAM only).	0.48/0.19	0.54/0.20	0.54/0.20	ns, Min
T _{RCKC_WREN} / T _{RCKC_WREN}	WREN FIFO inputs.	0.46/0.35	0.47/0.43	0.47/0.43	ns, Min
T _{RCKC_RDEN} / T _{RCKC_RDEN}	RDEN FIFO inputs.	0.43/0.35	0.43/0.43	0.43/0.43	ns, Min
Reset Delays					
T _{RCO_FLAGS}	Reset RST to FIFO flags/pointers. ⁽⁹⁾	0.98	1.10	1.10	ns, Max
T _{RREC_RST} /T _{RREM_RST}	FIFO reset recovery and removal timing. ⁽¹⁰⁾	2.07/–0.81	2.37/–0.81	2.37/–0.81	ns, Max
Maximum Frequency					
F _{MAX_BRAM_WF_NC}	Block RAM (write first and no change modes) when not in SDP RF mode.	460.83	388.20	388.20	MHz
F _{MAX_BRAM_RF_PERFORMANCE}	Block RAM (read first, performance mode) when in SDP RF mode but no address overlap between port A and port B.	460.83	388.20	388.20	MHz
F _{MAX_BRAM_RF_DELAYED_WRITE}	Block RAM (read first, delayed write mode) when in SDP RF mode and there is possibility of overlap between port A and port B addresses.	404.53	339.67	339.67	MHz
F _{MAX_CAS_WF_NC}	Block RAM cascade (write first, no change mode) when cascade but not in RF mode.	418.59	345.78	345.78	MHz
F _{MAX_CAS_RF_PERFORMANCE}	Block RAM cascade (read first, performance mode) when in cascade with RF mode and no possibility of address overlap/one port is disabled.	418.59	345.78	345.78	MHz

DSP48E1 Switching Characteristics

Table 31: DSP48E1 Switching Characteristics

Symbol	Description	V _{CCINT} Operating Voltage and Speed Grade			Units
		1.0V		0.95V	
		-2	-1	-1L	
Setup and Hold Times of Data/Control Pins to the Input Register Clock					
T _{DSPDCK_A_AREG} / T _{DSPCKD_A_AREG}	A input to A register CLK.	0.30/ 0.13	0.37/ 0.14	0.37/ 0.14	ns
T _{DSPDCK_B_BREG} / T _{DSPCKD_B_BREG}	B input to B register CLK.	0.38/ 0.16	0.45/ 0.18	0.45/ 0.18	ns
T _{DSPDCK_C_CREG} / T _{DSPCKD_C_CREG}	C input to C register CLK.	0.20/ 0.19	0.24/ 0.21	0.24/ 0.21	ns
T _{DSPDCK_D_DREG} / T _{DSPCKD_D_DREG}	D input to D register CLK.	0.32/ 0.27	0.42/ 0.27	0.42/ 0.27	ns
T _{DSPDCK_ACIN_AREG} / T _{DSPCKD_ACIN_AREG}	ACIN input to A register CLK.	0.27/ 0.13	0.32/ 0.14	0.32/ 0.14	ns
T _{DSPDCK_BCIN_BREG} / T _{DSPCKD_BCIN_BREG}	BCIN input to B register CLK.	0.29/ 0.16	0.36/ 0.18	0.36/ 0.18	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock					
T _{DSPDCK_{A, B}_MREG_MULT} / T _{DSPCKD_{A, B}_MREG_MULT}	{A, B} input to M register CLK using multiplier.	2.76/ −0.01	3.29/ −0.01	3.29/ −0.01	ns
T _{DSPDCK_{A, D}_ADREG} / T _{DSPCKD_{A, D}_ADREG}	{A, D} input to AD register CLK.	1.48/ −0.02	1.76/ −0.02	1.76/ −0.02	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock					
T _{DSPDCK_{A, B}_PREG_MULT} / T _{DSPCKD_{A, B}_PREG_MULT}	{A, B} input to P register CLK using multiplier.	4.60/ −0.28	5.48/ −0.28	5.48/ −0.28	ns
T _{DSPDCK_D_PREG_MULT} / T _{DSPCKD_D_PREG_MULT}	D input to P register CLK using multiplier.	4.50/ −0.73	5.35/ −0.73	5.35/ −0.73	ns
T _{DSPDCK_{A, B}_PREG} / T _{DSPCKD_{A, B}_PREG}	A or B input to P register CLK not using multiplier.	1.98/ −0.28	2.35/ −0.28	2.35/ −0.28	ns
T _{DSPDCK_C_PREG} / T _{DSPCKD_C_PREG}	C input to P register CLK not using multiplier.	1.76/ −0.26	2.10/ −0.26	2.10/ −0.26	ns
T _{DSPDCK_PCIN_PREG} / T _{DSPCKD_PCIN_PREG}	PCIN input to P register CLK.	1.51/ −0.15	1.80/ −0.15	1.80/ −0.15	ns
Setup and Hold Times of the CE Pins					
T _{DSPDCK_{CEA;CEB}_{AREG;BREG}} / T _{DSPCKD_{CEA;CEB}_{AREG;BREG}}	{CEA; CEB} input to {A; B} register CLK.	0.42/ 0.08	0.52/ 0.11	0.52/ 0.11	ns
T _{DSPDCK_CEC_CREG} / T _{DSPCKD_CEC_CREG}	CEC input to C register CLK.	0.34/ 0.11	0.42/ 0.13	0.42/ 0.13	ns
T _{DSPDCK_CED_DREG} / T _{DSPCKD_CED_DREG}	CED input to D register CLK.	0.43/ −0.03	0.52/ −0.03	0.52/ −0.03	ns

Device Pin-to-Pin Output Parameter Guidelines

Table 39: Clock-Capable Clock Input to Output Delay Without MMCM/PLL (Near Clock Region)⁽¹⁾

Symbol	Description	Device	V _{CCINT} Operating Voltage and Speed Grade			Units
			1.0V		0.95V	
			-2	-1	-1L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>without</i> MMCM/PLL.						
T _{ICKOF}	Clock-capable clock input and OUTFF at pins/banks closest to the BUFGs <i>without</i> MMCM/PLL (near clock region). ⁽²⁾	XC7S6	5.55	6.50	6.50	ns
		XC7S15	5.55	6.50	6.50	ns
		XC7S25	5.55	6.44	6.44	ns
		XC7S50	5.71	6.62	6.62	ns
		XC7S75	5.73	6.71	6.71	ns
		XC7S100	5.73	6.71	6.71	ns
		XA7S6	5.55	6.50	N/A	ns
		XA7S15	5.55	6.50	N/A	ns
		XA7S25	5.55	6.44	N/A	ns
		XA7S50	5.71	6.62	N/A	ns
		XA7S75	5.73	6.71	N/A	ns
		XA7S100	5.73	6.71	N/A	ns

Notes:

1. This table lists representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Refer to the *Die Level Bank Numbering Overview* section of the *7 Series FPGA Packaging and Pinout Specification* (UG475) [Ref 4].

Table 42: Clock-Capable Clock Input to Output Delay With PLL⁽¹⁾

Symbol	Description	Device	V _{CCINT} Operating Voltage and Speed Grade			Units
			1.0V		0.95V	
			-2	-1	-1L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>with</i> PLL.						
T _{ICKOFFLLCC}	Clock-capable clock input and OUTFF <i>with</i> PLL. ⁽²⁾	XC7S6	0.85	0.85	0.85	ns
		XC7S15	0.85	0.85	0.85	ns
		XC7S25	0.83	0.83	0.83	ns
		XC7S50	0.83	0.83	0.83	ns
		XC7S75	0.83	0.83	0.83	ns
		XC7S100	0.83	0.83	0.83	ns
		XA7S6	0.85	0.85	N/A	ns
		XA7S15	0.85	0.85	N/A	ns
		XA7S25	0.83	0.83	N/A	ns
		XA7S50	0.83	0.83	N/A	ns
		XA7S75	0.83	0.83	N/A	ns
		XA7S100	0.83	0.83	N/A	ns

Notes:

1. This table lists representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. PLL output jitter is already included in the timing calculation.

Table 43: Pin-to-Pin, Clock-to-Out using BUFIO

Symbol	Description	V _{CCINT} Operating Voltage and Speed Grade			Units
		1.0V		0.95V	
		-2	-1	-1L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, with BUFIO.					
T _{ICKOFCS}	Clock to out of I/O clock.	5.61	6.64	6.64	ns

Device Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. Values are expressed in nanoseconds unless otherwise noted.

Table 44: Global Clock Input Setup and Hold Without MMCM/PLL with ZHOLD_DELAY on HR I/O Banks

Symbol	Description	Device	V _{CCINT} Operating Voltage and Speed Grade			Units
			1.0V		0.95V	
			-2	-1	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for SSTL15 Standard. ⁽¹⁾						
T _{PSFD} / T _{PHFD}	Full delay (legacy delay or default delay) global clock input and IFF ⁽²⁾ without MMCM/PLL with ZHOLD_DELAY on HR I/O banks.	XC7S6	2.76/−0.40	3.17/−0.40	3.17/−0.40	ns
		XC7S15	2.76/−0.40	3.17/−0.40	3.17/−0.40	ns
		XC7S25	2.67/−0.37	3.12/−0.37	3.12/−0.37	ns
		XC7S50	2.66/−0.28	3.11/−0.28	3.11/−0.28	ns
		XC7S75	2.91/−0.33	3.36/−0.33	3.36/−0.33	ns
		XC7S100	2.91/−0.33	3.36/−0.33	3.36/−0.33	ns
		XA7S6	2.76/−0.40	3.17/−0.40	N/A	ns
		XA7S15	2.76/−0.40	3.17/−0.40	N/A	ns
		XA7S25	2.67/−0.37	3.12/−0.37	N/A	ns
		XA7S50	2.66/−0.28	3.11/−0.28	N/A	ns
		XA7S75	2.91/−0.33	3.36/−0.33	N/A	ns
		XA7S100	2.91/−0.33	3.36/−0.33	N/A	ns

Notes:

- Setup and hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the global clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the global clock input signal using the fastest process, lowest temperature, and highest voltage.
- IFF = Input flip-flop or latch.

Table 46: Clock-Capable Clock Input Setup and Hold With PLL

Symbol	Description	Device	V _{CCINT} Operating Voltage and Speed Grade			Units
			1.0V		0.95V	
			-2	-1	-1L	
Input Setup and Hold Time Relative to Clock-Capable Clock Input Signal for SSTL15 Standard. ⁽¹⁾⁽²⁾						
T _{PSPLLCC} / T _{PHPLLCC}	No delay clock-capable clock input and IFF ⁽³⁾ with PLL.	XC7S6	3.07/−0.17	3.69/−0.17	3.69/−0.17	ns
		XC7S15	3.07/−0.17	3.69/−0.17	3.69/−0.17	ns
		XC7S25	3.04/−0.19	3.64/−0.19	3.64/−0.19	ns
		XC7S50	3.15/−0.19	3.77/−0.19	3.77/−0.19	ns
		XC7S75	3.15/−0.19	3.78/−0.19	3.78/−0.19	ns
		XC7S100	3.15/−0.19	3.78/−0.19	3.78/−0.19	ns
		XA7S6	3.07/−0.17	3.69/−0.17	N/A	ns
		XA7S15	3.07/−0.17	3.69/−0.17	N/A	ns
		XA7S25	3.04/−0.19	3.64/−0.19	N/A	ns
		XA7S50	3.15/−0.19	3.77/−0.19	N/A	ns
		XA7S75	3.15/−0.19	3.78/−0.19	N/A	ns
		XA7S100	3.15/−0.19	3.78/−0.19	N/A	ns

Notes:

- Setup and hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the global clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the global clock input signal using the fastest process, lowest temperature, and highest voltage.
- Use IBIS to determine any duty-cycle distortion incurred using various standards.
- IFF = Input flip-flop or latch.

Table 47: Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFIO

Symbol	Description	V _{CCINT} Operating Voltage and Speed Grade			Units
		1.0V		0.95V	
		-2	-1	-1L	
Input Setup and Hold Time Relative to a Forwarded Clock Input Pin Using BUFIO for SSTL15 Standard.					
T _{PSCS} /T _{PHCS}	Setup and hold of I/O clock.	−0.38/1.46	−0.38/1.73	−0.38/1.76	ns

Table 48: Sample Window

Symbol	Description	V _{CCINT} Operating Voltage and Speed Grade			Units
		1.0V		0.95V	
		-2	-1	-1L	
T _{SAMP}	Sampling error at receiver pins. ⁽¹⁾	0.64	0.70	0.70	ns
T _{SAMP_BUFIO}	Sampling error at receiver pins using BUFIO. ⁽²⁾	0.40	0.46	0.46	ns

Notes:

1. This parameter indicates the total sampling error of the Spartan-7 FPGAs DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include:
 - CLK0 MMCM jitter
 - MMCM accuracy (phase offset)
 - MMCM phase shift resolution
These measurements do not include package or clock tree skew.
2. This parameter indicates the total sampling error of the Spartan-7 FPGAs DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFIO clock network and IDELAY to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

Configuration Switching Characteristics

Table 51: Configuration Switching Characteristics

Symbol	Description	V _{CCINT} Operating Voltage and Speed Grade			Units
		1.0V		0.95V	
		-2	-1	-1L	
Power-up Timing Characteristics					
T _{PL} ⁽¹⁾	Program latency.	5.00	5.00	5.00	ms, Max
T _{POR} ⁽²⁾	Power-on reset (50 ms ramp rate time).	10/50	10/50	10/50	ms, Min/Max
	Power-on reset (1 ms ramp rate time).	10/35	10/35	10/35	ms, Min/Max
T _{PROGRAM}	Program pulse width.	250.00	250.00	250.00	ns, Min
CCLK Output (Master Mode)					
T _{ICCK}	Master CCLK output delay.	150.00	150.00	150.00	ns, Min
T _{MCCKL}	Master CCLK clock Low time duty cycle.	40/60	40/60	40/60	%, Min/Max
T _{MCCKH}	Master CCLK clock High time duty cycle.	40/60	40/60	40/60	%, Min/Max
F _{MCCK}	Master CCLK frequency.	100.00	100.00	100.00	MHz, Max
	Master CCLK frequency for AES encrypted x16. ⁽²⁾	50.00	50.00	50.00	MHz, Max
F _{MCCK_START}	Master CCLK frequency at start of configuration.	3.00	3.00	3.00	MHz, Typ
F _{MCCKTOL}	Frequency tolerance, master mode with respect to nominal CCLK.	±50	±50	±50	%, Max
CCLK Input (Slave Modes)					
T _{SCCKL}	Slave CCLK clock minimum Low time.	2.50	2.50	2.50	ns, Min
T _{SCCKH}	Slave CCLK clock minimum High time.	2.50	2.50	2.50	ns, Min
F _{SCCK}	Slave CCLK frequency.	100.00	100.00	100.00	MHz, Max
EMCCLK Input (Master Mode)					
T _{EMCCKL}	External master CCLK Low time.	2.50	2.50	2.50	ns, Min
T _{EMCCKH}	External master CCLK High time.	2.50	2.50	2.50	ns, Min
F _{EMCCK}	External master CCLK frequency.	100.00	100.00	100.00	MHz, Max
Internal Configuration Access Port					
F _{ICAPCK}	Internal configuration access port (ICAPE2) clock frequency.	100.00	100.00	100.00	MHz, Max
Master/Slave Serial Mode Programming Switching					
T _{DCCK} / T _{CCKD}	D _{IN} setup/hold.	4.00/0.00	4.00/0.00	4.00/0.00	ns, Min
T _{CCO}	D _{OUT} clock to out.	8.00	8.00	8.00	ns, Max
SelectMAP Mode Programming Switching					
T _{SMDCK} / T _{SMCKD}	D[31:00] setup/hold.	4.00/0.00	4.00/0.00	4.00/0.00	ns, Min

eFUSE Programming Conditions

Table 52 lists the programming conditions specifically for eFUSE. For more information, see the *7 Series FPGA Configuration User Guide* (UG470) [Ref 10].

Table 52: eFUSE Programming Conditions⁽¹⁾

Symbol	Description	Min	Typ	Max	Units
I_{FS}	V_{CCAUX} supply current	–	–	115	mA
T_j	Temperature range	15	–	125	°C

Notes:

1. The FPGA must not be configured during eFUSE programming.

References

1. *7 Series FPGAs Overview* ([DS180](#))
2. *XA Spartan-7 Automotive FPGA Data Sheet: Overview* ([DS171](#))
3. *7 Series FPGAs SelectIO Resources User Guide* ([UG471](#))
4. *7 Series FPGA Packaging and Pinout Specification* ([UG475](#))
5. *7 Series FPGAs PCB Design Guide* ([UG483](#))
6. *Xilinx Power Estimator* spreadsheet tool ([XPE](#))
7. *Zynq-7000 AP SoC and 7 Series FPGAs Memory Interface Solutions User Guide* ([UG586](#))
8. See the [Clocking Wizard](#) in Vivado software.
9. *7 Series FPGAs and Zynq-7000 AP SoC XADC Dual 12-Bit 1 MSPS Analog-to-Digital Converter User Guide* ([UG480](#))
10. *7 Series FPGA Configuration User Guide* ([UG470](#))